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October 2013

# **FQB34N20**

# N-Channel QFET® MOSFET

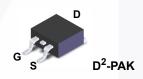
200 V, 31 A, 75 mΩ

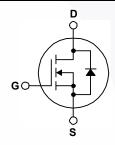
### **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

### **Features**

- 31 A, 200 V,  $R_{DS(on)}$  = 75 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 15.5 A
- Low Gate Charge (Typ. 60 nC)
- Low Crss (Typ. 55 pF)
- 100% Avalanche Tested
- RoHS Complianty





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

| Symbol                            | Parameter   |          | FQB34N20TM_AM002 | Unit |
|-----------------------------------|---|----------|------------------|------|
| V <sub>DSS</sub>                  | Drain-Source Voltage  |          | 200              | V    |
| I <sub>D</sub>                    | Drain Current - Continuous (T <sub>C</sub> = 25°                              | C)       | 31               | Α    |
|                                   | - Continuous (T <sub>C</sub> = 100  | )°C)     | 20               | Α    |
| I <sub>DM</sub>                   | Drain Current - Pulsed  | (Note 1) | 124              | Α    |
| V <sub>GSS</sub>                  | Gate-Source Voltage   |          | ± 30             | V    |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy  | (Note 2) | 640              | mJ   |
| I <sub>AR</sub>                   | Avalanche Current   | (Note 1) | 31               | Α    |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy   | (Note 1) | 18               | mJ   |
| dv/dt                             | Peak Diode Recovery dv/dt (Note 3)  |          | 5.5              | V/ns |
| $P_{D}$                           | Power Dissipation (T <sub>A</sub> = 25°C) *                                   |          | 3.13             | W    |
|                                   | Power Dissipation (T <sub>C</sub> = 25°C)                                     |          | 180              | W    |
|                                   | - Derate above 25°C   |          | 1.43             | W/°C |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Temperature Range                                       |          | -55 to +150      | °C   |
| T <sub>L</sub>                    | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds |          | 300              | °C   |

## **Thermal Characteristics**

| Symbol          | Parameter  | FQB34N20TM_AM002 | Unit |
|-----------------|--|------------------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case, Max.                                 | 0.7              | _    |
| В               | Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max. | 62.5             | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (* 1 in² pad of 2 oz copper), Max. | 40               |      |

# **Package Marking and Ordering Information**

| Device Marking | Device Marking Device |        | Reel Size | Tape Width | Quantity |  |
|----------------|-----------------------|--------|-----------|------------|----------|--|
| FQB34N20       | FQB34N20TM_AM002      | D2-PAK | 330mm     | 24mm       | 800      |  |

| ectrical Characteristics T <sub>C</sub> = 25°C unless otherwise noted |
|---|
| ECHICAL CHAPACLERISTICS T <sub>C</sub> = 25°C unle                    |

| Symbol                                  | Parameter                                    | lest Conditions                                 | Wiin | іур | wax  | Unit |
|---|--|---|------|-----|------|------|
| Off Cha                                 | aracteristics                                |   |      |     |      |      |
| BV <sub>DSS</sub>                       | Drain-Source Breakdown Voltage               | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$   | 200  |     |      | V    |
| ΔBV <sub>DSS</sub><br>/ ΔT <sub>J</sub> | Breakdown Voltage Temperature<br>Coefficient | I <sub>D</sub> = 250 μA, Referenced to 25°C     |      | 0.2 |      | V/°C |
| I <sub>DSS</sub>                        | OSS Zoro Coto Voltago Proin Current          | V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V  |      |     | 1    | μΑ   |
|   | Zero Gate Voltage Drain Current              | V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C |      |     | 10   | μΑ   |
| I <sub>GSSF</sub>                       | Gate-Body Leakage Current, Forward           | V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V   |      |     | 100  | nA   |
| I <sub>GSSR</sub>                       | Gate-Body Leakage Current, Reverse           | V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V  |      |     | -100 | nA   |

| $V_{GS(th)}$        | Gate Threshold Voltage               | $V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$     | 3.0 |      | 5.0   | V |
|---------------------|--------------------------------------|---|-----|------|-------|---|
| R <sub>DS(on)</sub> | Static Drain-Source<br>On-Resistance | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15.5 A |     | 0.06 | 0.075 | Ω |
| 9 <sub>FS</sub>     | Forward Transconductance             | $V_{DS} = 40 \text{ V}, I_{D} = 15.5 \text{ A}$ | -   | 25   |       | S |

### **Dynamic Characteristics**

| $C_{iss}$        | Input Capacitance            | $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ | <br>2400 | 3100 | pF |
|------------------|------------------------------|--|----------|------|----|
| Coss             | Output Capacitance           | f = 1.0 MHz                                    | <br>430  | 560  | pF |
| C <sub>rss</sub> | Reverse Transfer Capacitance |  | <br>55   | 70   | pF |

### **Switching Characteristics**

| t <sub>d(on)</sub>  | Turn-On Delay Time  | V <sub>DD</sub> = 100 V, I <sub>D</sub> = 34 A, |        |   | 40  | 90  | ns |
|---------------------|---------------------|---|--------|---|-----|-----|----|
| t <sub>r</sub>      | Turn-On Rise Time   | $R_{\rm G} = 25 \ \Omega$                       |        |   | 280 | 570 | ns |
| t <sub>d(off)</sub> | Turn-Off Delay Time |   |        |   | 125 | 260 | ns |
| t <sub>f</sub>      | Turn-Off Fall Time  | (No   | ote 4) | / | 115 | 240 | ns |
| Qg                  | Total Gate Charge   | V <sub>DS</sub> = 160 V, I <sub>D</sub> = 34 A, |        |   | 60  | 78  | nC |
| $Q_{gs}$            | Gate-Source Charge  | V <sub>GS</sub> = 10 V                          |        |   | 17  | -   | nC |
| $Q_{gd}$            | Gate-Drain Charge   | (No   | ote 4) |   | 27  | -   | nC |

### **Drain-Source Diode Characteristics and Maximum Ratings**

| Is              | Maximum Continuous Drain-Source Diode Forward Current |   |  |      | 31  | Α  |
|-----------------|---|---|--|------|-----|----|
| I <sub>SM</sub> | Maximum Pulsed Drain-Source Diode Forward Current     |   |  |      | 124 | Α  |
| V <sub>SD</sub> | Drain-Source Diode Forward Voltage                    | V <sub>GS</sub> = 0 V, I <sub>S</sub> = 31 A  |  |      | 1.5 | V  |
| t <sub>rr</sub> | Reverse Recovery Time                                 | V <sub>GS</sub> = 0 V, I <sub>S</sub> = 34 A, |  | 150  |     | ns |
| Q <sub>rr</sub> | Reverse Recovery Charge                               | dI <sub>F</sub> / dt = 100 A/μs               |  | 0.95 |     | μC |

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.0mH,  $I_{AS}$  = 31A,  $V_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C 3.  $I_{SD}$  ≤ 34A, di/dt ≤ 300A/ $\mu$ s,  $V_{DD}$  ≤ BV $_{DSS}$ , Starting  $T_{J}$  = 25°C 4. Essentially independent of operating temperature

# **Typical Characteristics**

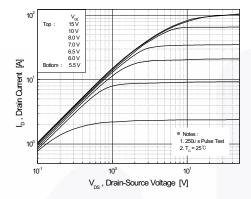


Figure 1. On-Region Characteristics

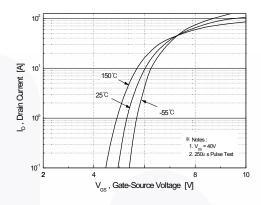


Figure 2. Transfer Characteristics

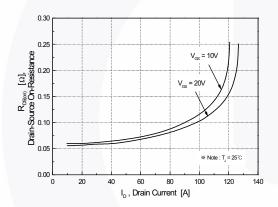


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

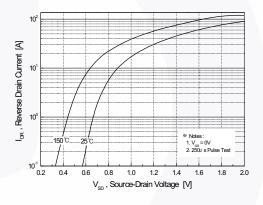


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

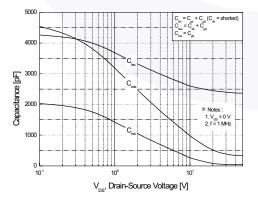


Figure 5. Capacitance Characteristics

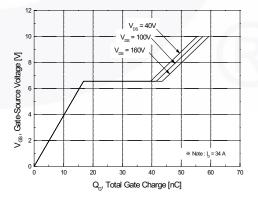


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)

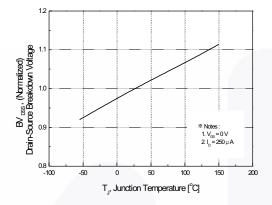


Figure 7. Breakdown Voltage Variation vs. Temperature

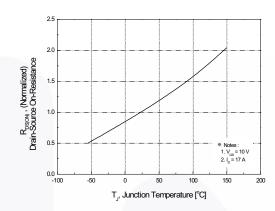


Figure 8. On-Resistance Variation vs. Temperature

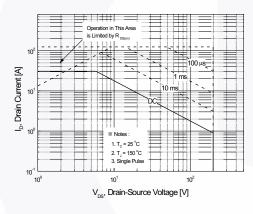


Figure 9. Maximum Safe Operating Area

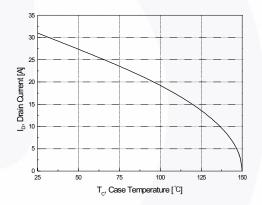


Figure 10. Maximum Drain Current vs. Case Temperature

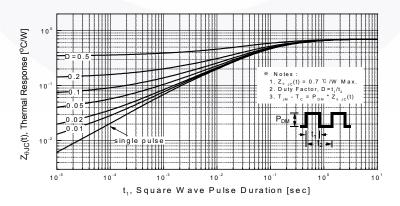


Figure 11. Transient Thermal Response Curve



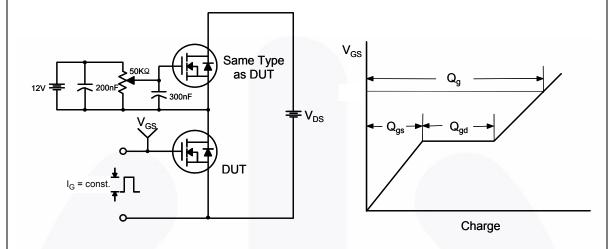


Figure 13. Resistive Switching Test Circuit & Waveforms

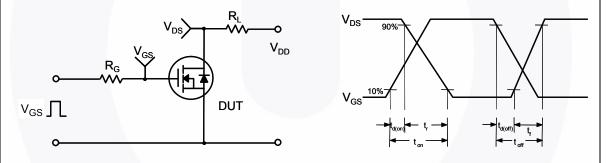
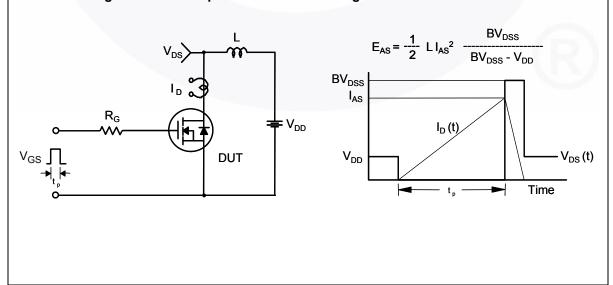
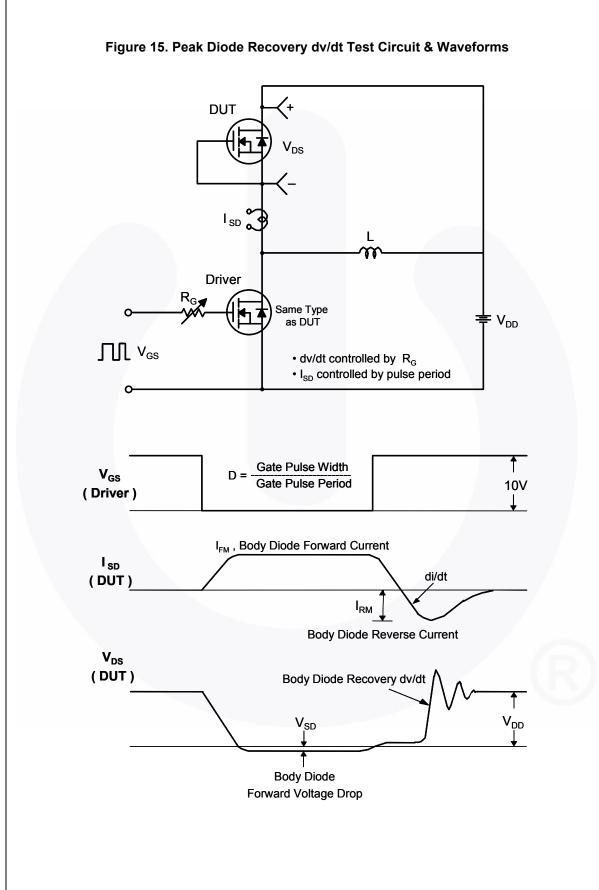


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms





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### **Mechanical Dimensions**

# TO-263 2L (D<sup>2</sup>PAK)

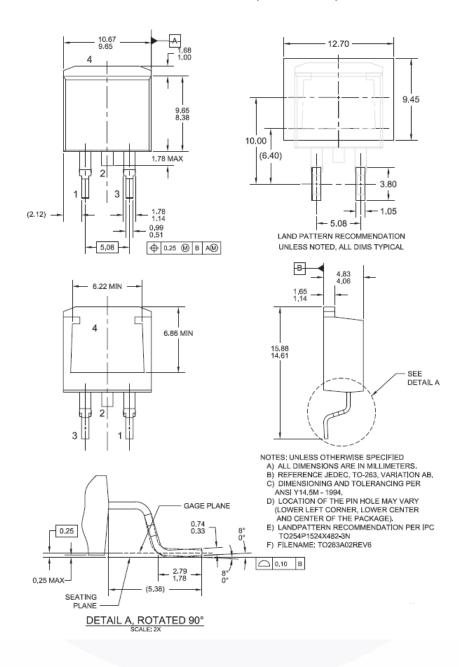


Figure 16. 2LD, TO263, Surface Mount

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Dimension in Millimeters





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